


<b>Search Notes</b> 	<b>Application/Control No.</b> 10598971	<b>Applicant(s)/Patent Under Reexamination</b> OSHIYAMA ET AL.
	<b>Examiner</b> Vu Nguyen	<b>Art Unit</b> 1796

SEARCHED			
Class	Subclass	Date	Examiner
546	10	1/20/2010	/V.N./
	13		
	84		
428	690		
	917		
313	504		
	506		
257	E51.041	1/20/2010	/V.N./

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor search (eDAN, PALM, EAST)	1/8/2010	/V.N./
See STIC Search results	1/13/2010	/V.N./
See EAST search report	1/20/2010	/V.N./
Google search	1/19/2010	/V.N./

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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Examiner, Art Unit 1796